

PATENT

DK-US065116

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Junko TAKAHASHI et al.

Serial No.: New – (National Phase of
PCT/JP2004/017779)

International filing date: November 30, 2004

For: METHOD OF EXAMINING CHEMICAL
USING GENE-DISRUPTED STRAIN

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner of Patents
Washington, DC 20231

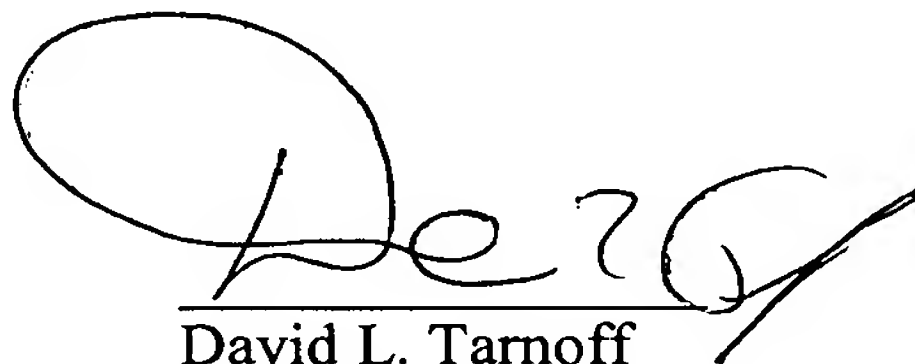
Sir:

In accordance with MPEP 609 and 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicants bring the references listed on the attached PTO-1449-Form to the Examiner's attention and request that they be considered and made of record in this application. Copies of the non-U.S. patents are attached.

* * *

Prompt examination on the merits is respectfully requested.

Respectfully submitted,


David L. Tarnoff
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Dated: 5-31-06

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet

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of

1

Complete if Known

Application Number

PCT/JP2004/017779

Filing Date

International Date of November 30, 2004

First Named Inventor

Junko TAKAHASHI

Group Art Unit

Examiner Name

Attorney Docket Number

DK-US065116

[illegible]

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)				
		JP-2001-095596-A	04-10-2001	Iwama		Yes
		JP-2001-238694-A	09-04-2001	Iwahashi et al.		Yes
		JP-2001-286281-A	10-16-2001	Iwahashi et al.		Yes
		WO-03-018791-A1	03-06-2003	Iwahashi et al.		Yes
		WO-03-018792-A1	03-06-2003	Iwahashi et al.		Yes

**Examiner
Signature**

Date Considered

***EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04.

³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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